

<u>AP80N03D</u>



useon

Description

The AP80N03D uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

V_{DS} = 30V I_D =80 A

 $R_{DS(ON)} < 6m\Omega @ V_{GS}=10V$

Application

Battery protection

Load switch

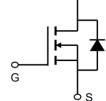
Uninterruptible power supply

Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP80N03D	TO-252-3L	AP80N03D XXX YYYY	2500

Absolute Maximum Ratings (Tc=25°Cunless otherwise noted)

Symbol	Parameter	Rating	Units
Vds	Drain-Source Voltage	30	V
Vgs	Gate-Source Voltage	±20	V
	Drain Current – Continuous (Tc=25°C)	80	А
lo	Drain Current – Continuous (Tc=100°C)	51	А
IDM	Drain Current – Pulsed ¹	320	А
EAS	Single Pulse Avalanche Energy ²	88	mJ
IAS	Single Pulse Avalanche Current ²	42	А
_	Power Dissipation (T _c =25°C)	54	W
PD	Power Dissipation – Derate above 25°C	0.43	W/°C
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
R ₀ JA	Thermal Resistance Junction to ambient	62	°C/W
Rejc	Thermal Resistance Junction to Case	2.3	°C/W



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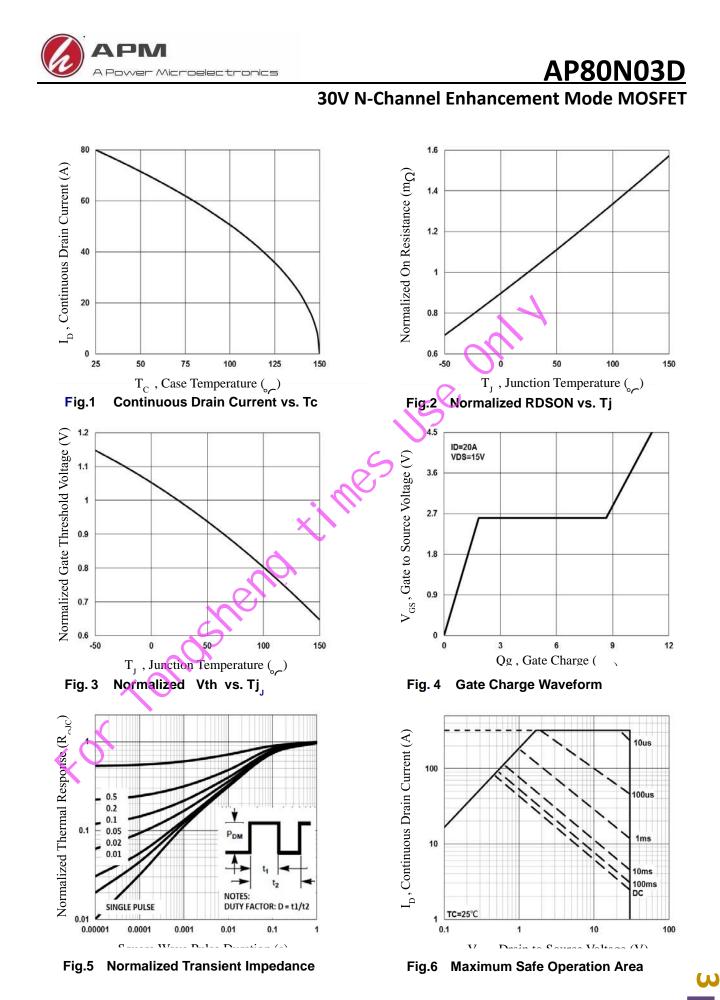
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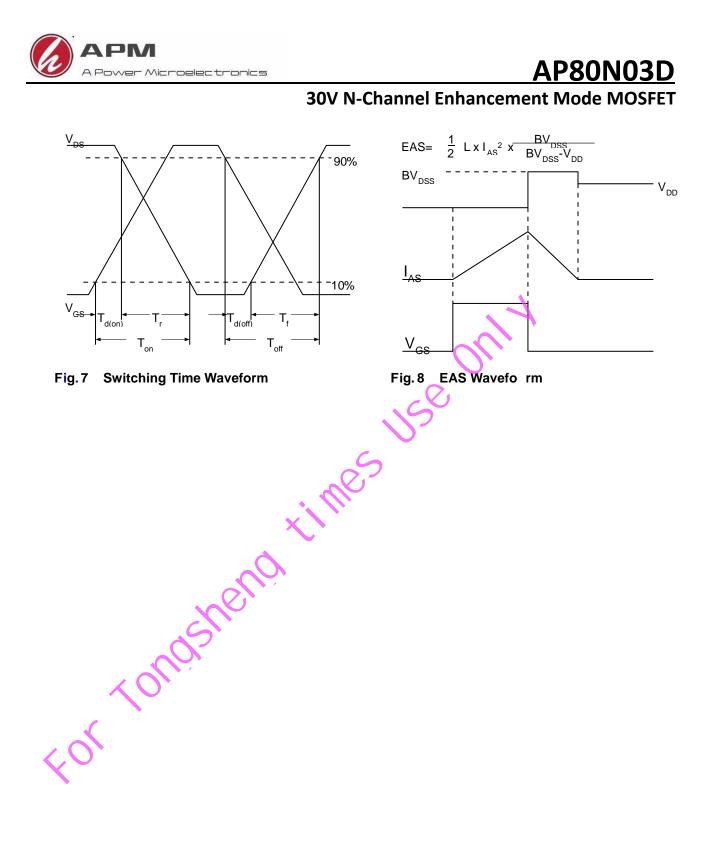
30V N-Channel Enhancement Mode MOSFET

Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V_{GS} =0V , I _D =250uA	30			V
∆BVDSS/∆TJ	BV _{DSS} Temperature Coefficient	Reference to 25 $^{\circ}$ C , I _D =1mA		0.04		V/°C
1500		V _{DS} =30V , V _{GS} =0V , T _J =25 [°] C			1	uA
IDSS	Drain-Source Leakage Current	V _{DS} =24V , V _{GS} =0V , T _J =125°C			10	uA
IGSS	Gate-Source Leakage Current	$V_{GS}=\pm 20V$, $V_{DS}=0V$			±100	nA
	Static Drain-Source On-Resistance ³	V _{GS} =10V , I _D =20A		4.8	6	mΩ
RDS(ON)		V _{GS} =4.5V , I _D =10A		6.5	9	mΩ
VGS(th)	Gate Threshold Voltage		1	1.6	2.5	V
$ riangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	$V_{GS}=V_{DS}$, $I_{D}=250$ uA		-4		mV/°C
gfs	Forward Transconductance	V _{DS} =10V , I _D =10A		18		s
Qg	Total Gate Charge ^{3,4}	5		11.1		
Qgs	Gate-Source Charge ^{3,4}	V _{DS} =15V, V _{GS} =4.5V , I _D =20A		1.85		nC
Qgd	Gate-Drain Charge ^{3,4}			6.8		
Td(on)	Turn-On Delay Time ^{3,4}			7.5		
T,	Rise Time ^{3,4} $V_{DD}=15V$, $V_{GS}=10V$, $R_G=3.3\Omega$ Turn-Off Delay Time ^{3,4} $I_D=15A$			14.5		ns
Td(off)				35.2		
T _f	Fall Time ^{3,4}			9.6		
Ciss	Input Capacitance	V_{DS} =25V , V_{GS} =0V , F=1MHz		1160		pF
Coss	Output Capacitance			200		
Crss	Reverse Transfer Capacitance			180		
R _g	Gate resistance	V _{GS} =0V, V _{DS} =0V, F=1MHz		2.5		Ω
EAS	Single Pulse Avalanche Energy	V _{DD} =25V, L=0.1mH, IAS=20A				mJ
IS	Continuous Source Current	$V_{G}=V_{D}=0V$, Force Current			80	А
ISM	Pulsed Source Current ³				320	А
VSD	Diode Forward Voltage ³	V _{GS} =0V , I _S =1A , T _J =25°C			1	V
trr	Reverse Recovery Time	VGS=0V,IS=1A , di/dt=100A/µs T _J =25°C				ns
Q _{rr}	Reverse Recovery Charge					nC

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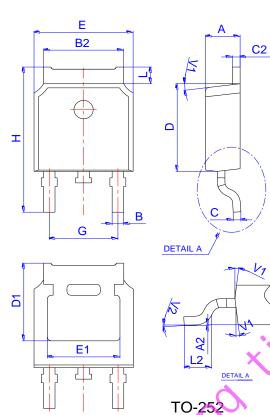
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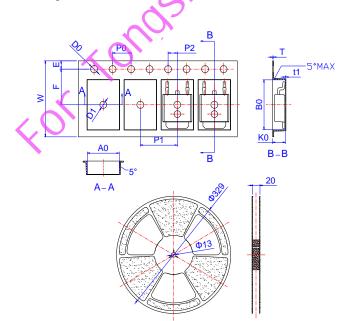
30V N-Channel Enhancement Mode MOSFET

Package Mechanical Data



	Dimensions						
Ref.	Millimeters			Inches			
	Min.	Тур.	Max.	Min.	Тур.	Max.	
A	2.10		2.50	0.083		0.098	
A2	0		0.10	0		0.004	
В	0.66		0.86	0.026		0.034	
B2	5.18		5.48	0.202		0.216	
С	0.40		0.60	0.016		0.024	
C2	0.44		0.58	0.017		0.023	
D	5.90		6.30	0.232		0.248	
D1		5.30REF		0.209REF			
E	6.40	0	6.80	0.252		0.268	
E1	4.63			0.182			
G	4.47		4.67	0.176		0.184	
F	9.50		10.70	0.374		0.421	
OL-	1.09		1.21	0.043		0.048	
L2	1.35		1.65	0.053		0.065	
V1		7°			7°		
V2	0°		6°	0°		6°	

Reel Spectification-TO-252



	Dimensions						
Ref.	Millimeters			Inches			
	Min.	Тур.	Max.	Min.	Тур.	Max.	
W	15.90	16.00	16.10	0.626	0.630	0.634	
E	1.65	1.75	1.85	0.065	0.069	0.073	
F	7.40	7.50	7.60	0.291	0.295	0.299	
D0	1.40	1.50	1.60	0.055	0.059	0.063	
D1	1.40	1.50	1.60	0.055	0.059	0.063	
P0	3.90	4.00	4.10	0.154	0.157	0.161	
P1	7.90	8.00	8.10	0.311	0.315	0.319	
P2	1.90	2.00	2.10	0.075	0.079	0.083	
A0	6.85	6.90	7.00	0.270	0.271	0.276	
B0	10.45	10.50	10.60	0.411	0.413	0.417	
K0	2.68	2.78	2.88	0.105	0.109	0.113	
Т	0.24		0.27	0.009		0.011	
t1	0.10			0.004			
10P0	39.80	40.00	40.20	1.567	1.575	1.583	

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AP80N03D

30V N-Channel Enhancement Mode MOSFET

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